<ul> <li>Dedicated PWM Input Port</li> <li>Optimized for Reversible Operation of</li> </ul>		WP PACKA (TOP VIEW	_
Motors	GNDS [	1 20	GNDS
<ul> <li>Two Input Control Lines for Reduced Microcontroller Overhead</li> </ul>	V <sub>CC</sub> [ DIR [		V <sub>CC</sub> STATUS2
<ul> <li>Internal Current Shutdown of 5 A</li> </ul>	V <sub>CC</sub> [	4 17	] v <sub>cc</sub>
<ul> <li>40 V Load Dump Rating</li> </ul>	9		OUT2
Integrated Fault Protection and Diagnostics	5		OUT2
	GND [	7 14	] GND
<ul> <li>CMOS Compatible Schmitt Trigger Inputs</li> </ul>	PWM [	8 13	STATUS1
for High Noise Immunity	GND [	9 12	GND
doscription	GNDS [	10 11	GNDS

#### description

The TPIC0107B is a PWM control intelligent H-bridge designed specifically for dc motor applications. The device provides forward, reverse, and brake modes of operation. A logic supply voltage of 5 V is internally derived from V<sub>CC</sub>.

The TPIC0107B has an extremely low  $r_{DS(on)}$ , 280 m $\Omega$  typical, to minimize system power dissipation. The direction control (DIR) and PWM control (PWM) inputs greatly simplify the microcontroller overhead requirement. The PWM input can be driven from a dedicated PWM port while the DIR input is driven as a simple low speed toggle.

The TPIC0107B provides protection against over-voltage, over-current, over-temperature, and cross conduction faults. Fault diagnostics can be obtained by monitoring the STATUS1 and STATUS2 terminals and the two input control lines. STATUS1 is an open-drain output suitable for wired-or connection. STATUS2 is a push-pull output that provides a latched status output. Under-voltage protection ensures that the outputs, OUT1 and OUT2, will be disabled when V<sub>CC</sub> is less than the under-voltage detection voltage V<sub>(UVCC)</sub>.

The TPIC0107B is designed using TI's LinBiCMOS™ process. LinBiCMOS allows the integration of low power CMOS structures, precision bipolar cells, and low impedance DMOS transistors.

The TPIC0107B is offered in a 20-pin thermally enhanced small-outline package (DWP) and is characterized for operation over the operating case temperature of –40°C to 125°C.

DIR	PWM	OUT1	OUT2	MODE
0	0	HS	HS	Brake, both HSDs turned on ha
0	4	LIC	1.0	Matantiuma accuston algaliusiaa

#### Motor turns counter clockwise 0 HS 1 HS Brake, both HSDs turned on hard LS HS Motor turns clockwise

**FUNCTION TABLE** 

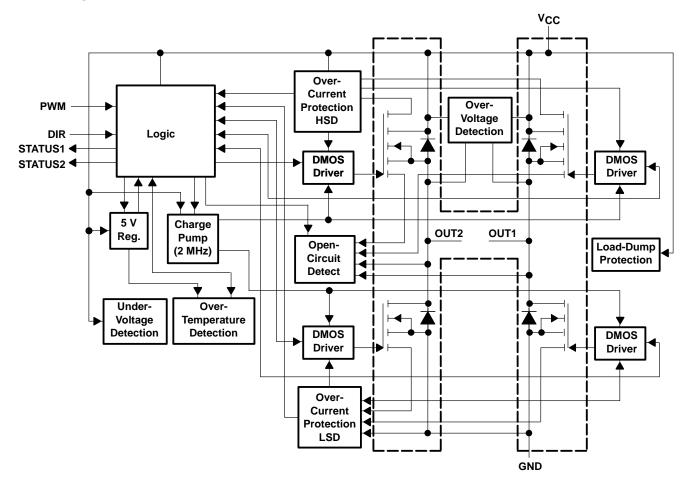


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

LinBiCMOS is a trademark of Texas Instruments Incorporated.



# block diagram



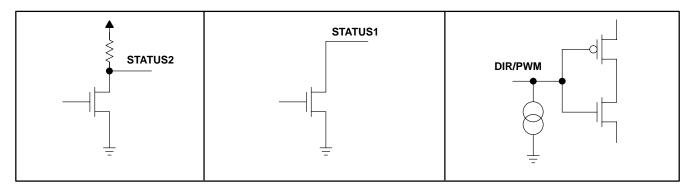
## **Terminal Functions**

TERM	IINAL	1,0	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
DIR	3	I	Direction control input
GND	7, 9, 12, 14	I	Power ground
GNDS	1, 10, 11, 20	I	Substrate ground
OUT1	5, 6	0	Half-H output. DMOS output
OUT2	15, 16	0	Half-H output. DMOS output
PWM	8	Т	PWM control input
STATUS1	13	0	Status output
STATUS2	18	0	Latched status output
VCC	2, 4, 17, 19	Ī	Supply voltage

NOTE: It is mandatory that all four ground terminals plus at least one substrate terminal are connected to the system ground. Use all V<sub>CC</sub> and OUT terminals.



# schematics of inputs and outputs



# absolute maximum ratings over operating case temperature range (unless otherwise noted)<sup>†</sup>

Power supply voltage range, V <sub>CC</sub>	0.3 V to 33 V
Logic input voltage range, V <sub>IN</sub>	0.3 V to 7 V
Load dump (for 400 ms, T <sub>C</sub> = 25°C)	40 V
Status output voltage range, V <sub>O(status)</sub>	0.3 V to 7 V
Continuous power dissipation, T <sub>C</sub> = 25°C	1.29 W
Storage temperature range, T <sub>stq</sub>	–55°C to 150°C
Maximum junction temperature, T <sub>J</sub>	150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### **DISSIPATION RATING TABLE**

T <sub>A</sub> ≤ 25°C	DERATING FACTOR	T <sub>A</sub> = 70°C	T <sub>A</sub> = 125°C
POWER RATING	ABOVE T <sub>A</sub> = 25°C	POWER RATING	POWER RATING
1.29 W	0.0104 W/°C	0.82 W	0.25 W

# recommended operating conditions

	MIN	MAX	UNIT
Supply voltage, V <sub>CC</sub>	6	18	V
Operating case temperature, T <sub>C</sub>	-40	125	°C
Switching frequency, f <sub>PWM</sub>		2	kHz

# electrical characteristics over recommended operating case temperature range and $V_{CC} = 5 \text{ V}$ to 6 V (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
		LSD	T <sub>J</sub> = 25°C			550		
   r=o,	Static drain-source on-resistance (per transistor)	LSD	T <sub>J</sub> = 150°C			850	mΩ	
rDS(on)	$I_{(BR)} = 1 A$	HSD	T <sub>J</sub> = 25°C			600	mΩ	
		пор	T <sub>J</sub> = 150°C			870	11152	
I(QCD)	Open circuit detection current		10	40	100	mA		
V(UVCC(OFF))	Under voltage detection on V <sub>CC</sub> , switch off voltage	1	See Note 1			5	V	
V(UVCC(ON))	Under voltage detection on V <sub>CC</sub> , switch on voltage		See Note 1			5.2	V	
V <sub>(STL)</sub>	STATUS low output voltage		$I_O = 100 \mu A$ , See Note 1			0.8	V	
V <sub>(ST2H)</sub>	STATUS2 high output voltage		$I_O = 20 \mu A$ , See Note 1	3		5.4	V	
I(ST(OFF))	STATUS output leakage current		V <sub>(ST)</sub> = 5 V, See Note 1			5	μΑ	
V <sub>IL</sub>	Low level logic input voltage			-0.3		0.5	V	
VIH	High level logic input voltage			3.6		7	V	
ΔVΙ	Hysteresis of input voltage			0.3			V	
lн	High level logic input current	·	V <sub>IH</sub> = 3.5 V	2	10	50	μΑ	

NOTE 1: The device functions according to the function table for  $V_{CC}$  between  $V_{(UVCC)}$  and 5 V (no parameters specified). STATUS outputs are not defined for V<sub>CC</sub> less than V<sub>(UVCC)</sub>.



# electrical characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted) (see Note 2)

PARAMETER			TEST CONDITIONS		MIN	TYP	MAX	UNIT
		LSD	T 25°C	V <sub>CC</sub> = 6 V to 9 V			380	
			T <sub>J</sub> = 25°C	V <sub>CC</sub> = 9 V to 18 V		280	340	$_{m\Omega}$
		LSD	T <sub>J</sub> = 150°C	$V_{CC} = 6 V to 9 V$			620	11152
 	Static drain-source on-resistance		1 J = 130 C	$V_{CC} = 9 V \text{ to } 18 V$		400	560	
rDS(on)	(per transistor) I <sub>BR</sub> = 1 A		T <sub>J</sub> = 25°C	$V_{CC} = 6 \text{ V to 9 V}$			430	
		HSD	1J = 25 C	V <sub>CC</sub> = 9 V to 18 V		280	340	mΩ
		1130	T <sub>.1</sub> = 150°C	$V_{CC} = 6 V \text{ to } 9 V$			640	11152
			1J = 150 C	V <sub>CC</sub> = 9 V to 18 V		400	560	
I(QCD)	Open circuit detection current				10	40	100	mA
T <sub>SDS</sub>	Static thermal shutdown temperature	е	See Notes 3 and 4		140			°C
T <sub>SDD</sub>	Dynamic thermal shutdown tempera	iture	See Notes 3 and 5	See Notes 3 and 5				°C
loo	Current shutdown limit		$V_{CC} = 6 V \text{ to } 9 V$		4.8		7.5	Α
lcs	Current shutdown limit		V <sub>CC</sub> = 9 V to 18 V		5		7.5	ζ
I <sub>(CON)</sub>	Continuous bridge current		T <sub>J</sub> = 125°C, Operating lifetime 10,000 hours, (see Figure 1)				3	Α
V(OVCC)	Over voltage detection on V <sub>CC</sub>				27		36	V
V(STL)	STATUS low output voltage		ΙΟ = 100 μΑ				0.8	V
V(ST2H)	STATUS2 high output voltage		I <sub>O</sub> = 20 μA		3.9		5.4	V
I(ST(OFF))	STATUS output leakage current		V <sub>(ST)</sub> = 5 V				5	μΑ
V <sub>IL</sub>	Low level logic input voltage				-0.3		0.8	V
$V_{IH}$	High level logic input voltage				3.6		7	V
$\Delta V_{\parallel}$	Hysteresis of input voltage				0.3			V
lн	High level logic input current		V <sub>IH</sub> = 3.5 V		2	10	50	μΑ

NOTES: 2. The device functions according to the function table for V<sub>CC</sub> between 18 V and V<sub>(OVCC)</sub>, but only up to a maximum supply voltage of 33 V (no parameters specified). Exposure beyond 18 V for extended periods may affect device reliability.

- 3. Exposure beyond absolute-maximum-rated condition of junction temperature may affect device reliability.
- 4. No temperature gradient between DMOS transistor and temperature sensor.
- 5. With temperature gradient between DMOS transistor and temperature sensor in a typical application (DMOS transistor as heat source).

# switching characteristics over recommended operating case temperature and supply voltage ranges (unless otherwise noted)

PARAMETER		TEST CONDITIONS		TYP	MAX	UNIT
+	High-side driver turn-on time	V=04 ×41 V 2t 1 A			100	116
<sup>t</sup> out(on)	Low-side driver turn-on time	$V_{DS(on)}$ <1 V at 1 A, $V_{CC}$ = 13.2 V			100	μs
ep.	Slew rate, low-to-high sinusoidal (δV/δt)	$V_{CC} = 13.2 \text{ V},$ $I_{CC} = 1 \text{ A resistive load}$	1		6	1//40
SR	Slew rate, high-to-low sinusoidal ( $\delta V/\delta t$ )	$V_{CC} = 13.2 \text{ V},$ $I_O = 1 \text{ A resistive load}$	1		6	V/μs
td(QCD)	Under current spike duration to trigger open circuit detection	V <sub>CC</sub> = 5 V to 18 V	1		10	ms
t <sub>d</sub> (CS)	Delay time for over current shutdown		5	10	25	μs

#### thermal resistance

	PARAMETER			UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance		97	°C/W
$R_{\theta JC}$	Junction-to-case thermal resistance		5	°C/W



# PARAMETER MEASUREMENT INFORMATION

Maximum continuous bridge current versus time based on 50 FITs at 100,000 hours operating life (90% confidence model)

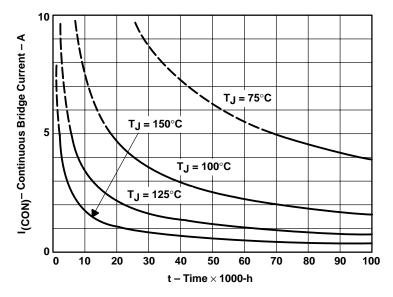


Figure 1. Electromigration Reliability Data

#### Example:

Average continuous bridge current, ICON	Average junction temperature, T <sub>J</sub>	Operating lifetime of device based on electromigration			
2 A	125°C	>20,000 h			
3 A	125°C	>10,000 h			



#### PARAMETER MEASUREMENT INFORMATION

# operating wave forms

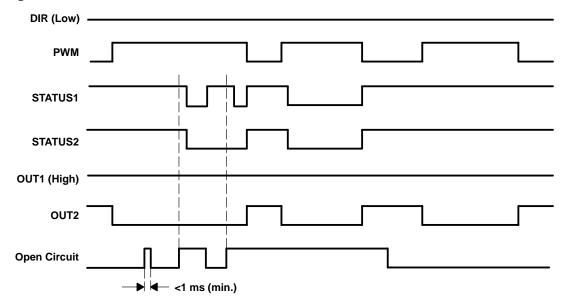


Figure 2. Open Circuit

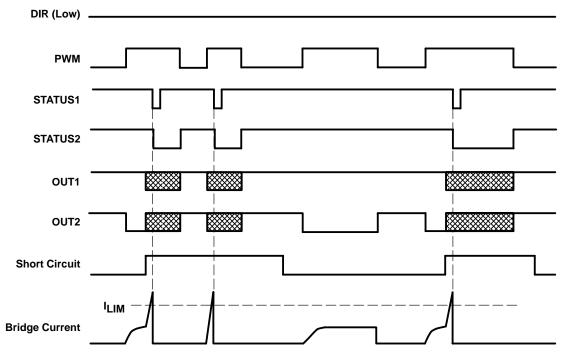


Figure 3. Short Circuit (e.g., OUT2 to V<sub>CC</sub>)

#### PARAMETER MEASUREMENT INFORMATION

# operating wave forms (continued) DIR (Low) PWM STATUS1 STATUS2 OUT1 OUT2 Over Temperature

Figure 4. Over Temperature

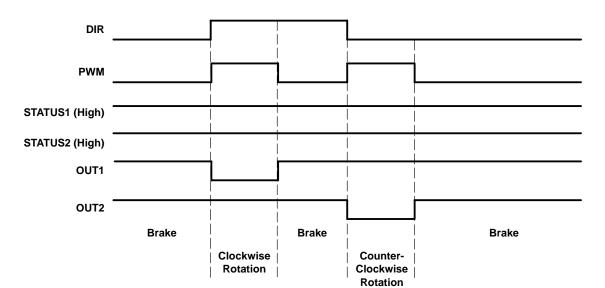


Figure 5. No Fault



#### PRINCIPLES OF OPERATION

## protective functions and diagnostics<sup>†</sup>

#### over current/short circuit‡

The TPIC0107B detects shorts to  $V_{CC}$ , ground, or across the load being driven, by comparing the  $V_{DS}$  voltage drop across the DMOS outputs against the threshold voltage. The DMOS outputs of the TPIC0107B will be disabled and the fault flags will be generated 10  $\mu$ s after an over-current or short-circuit fault is detected. This 10  $\mu$ s delay is long enough to serve as a de-glitch filter for high current transients, yet short enough to prevent damage to the DMOS outputs. The DMOS outputs remain latched off until either DIR or PWM input is toggled.

In cases where the outputs have a continuous short-to-ground with a current rise time faster than 0.5 A/ $\mu$ s, the over-current shutdown threshold will decrease to 3 A to reduce power dissipation. This reduction to 3 A is achieved since the DMOS outputs will not be fully enhanced when the over-current threshold is reached if the current rise time exceeds 0.5 A/ $\mu$ s. Over-current and/or short-circuit protection is provided up to V<sub>CC</sub> = 16.5 V and a junction temperature of 90°C.

#### over temperature

The TPIC0107B disables all DMOS outputs and the fault flags will be set when T<sub>J</sub> ≥140°C (min.). The DMOS outputs remain latched off until either DIR or PWM input is toggled.

#### under voltage

The TPIC0107B disables all DMOS outputs when  $V_{CC} \leq V_{(UVCC)}$ . The outputs will be re-enabled when  $V_{CC} \geq V_{(UVCC)}$ . No fault flags are set when under-voltage lockout occurs.

#### over voltage

In order to protect the DMOS outputs from damage caused by excessive supply voltage, the TPIC0107B disables all outputs when  $V_{CC} \ge V_{(OVCC)}$ . Once  $V_{CC} \le V_{(OVCC)}$ , either DIR or PWM input must be toggled to re-enable the DMOS outputs.

#### cross conduction

Monitoring circuitry for each transistor detects whether the particular transistor is active to prevent the HSD or LSD of the corresponding half H-bridge from conducting.

#### open circuit

During operation, the bridge current is controlled continuously. If the bridge current is >10 mA (min.) for a period >1 ms (min.), the fault flags are set. However, the output transistors will not be disabled.

<sup>‡</sup> If a short circuit occurs (i.e., the over-current detection circuitry is activated) at a supply voltage higher than 16.5 V and a junction temperature higher than 90°C, damage to the device may occur.



<sup>&</sup>lt;sup>†</sup> All limits mentioned are typical values unless otherwise noted.

#### PRINCIPLES OF OPERATION

#### **DIAGNOSTICS TABLE (see Note 6)**

FLAG	DIR	PWM	OUT1	OUT2	STATUS1 <sup>†</sup>	STATUS2
	0	0	HS	HS	1	1
Normal operation	0	1	HS	LS	1	1
Normal operation	1	0	HS	HS	1	1
	1	1	LS	HS	1	1
	0	0	HS	HS	1	1
Open circuit between OUT1 and OUT2	0	1	HS	LS	0	0
Spen circuit between 0011 and 0012	1	0	HS	HS	1	1
	1	1	LS	HS	0	0
Chart sirewit from OUT4 to OUT9 (and Notes 7 and 9)	0	1	Х	Х	0	0
Short circuit from OUT1 to OUT2 (see Notes 7 and 8)	1	1	Х	Х	0	0
	0	0	Х	Х	0	0
Short circuit from OUT1 to GND (see Notes 7 and 8)	1	0	Х	Х	0	0
	0	1	Х	Х	0	0
	0	0	Х	Х	0	0
Short circuit from OUT2 to GND (see Notes 7 and 8)	1	0	Х	Х	0	0
	1	1	Х	Х	0	0
Short circuit from OUT1 to V <sub>CC</sub> (see Notes 7 and 8)	1	1	Х	Х	0	0
Short circuit from OUT2 to V <sub>CC</sub> (see Notes 7 and 8)	0	1	Х	Х	0	0
	0	0	Z	Z	0	0
Over temperature	0	1	Z	Z	0	0
Over temperature	1	0	Z	Z	0	0
	1	1	Z	Z	0	0

†When wired with a pull-up resistor

SYMBOL VALUE 0 Logic low 1 Logic high

HS High-side MOSFET conducting LS Low-side MOSFET conducting Z No output transistors conducting

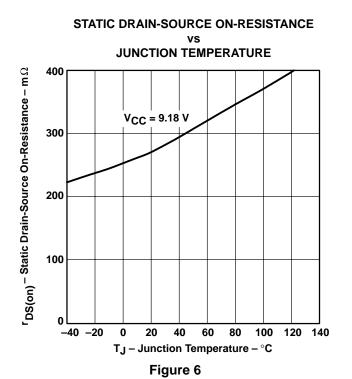
X Voltage level undefined

NOTES: 6. All input combinations not stated result in STATUS output = 1.

STATUS1 active for a minimum of 3 μs.
 STATUS2 active until an input is toggled.

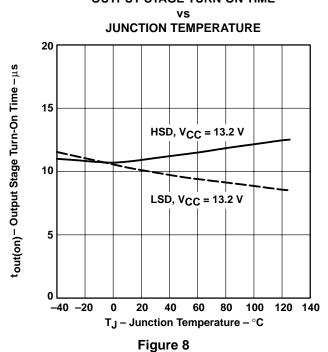


#### **TYPICAL CHARACTERISTICS**

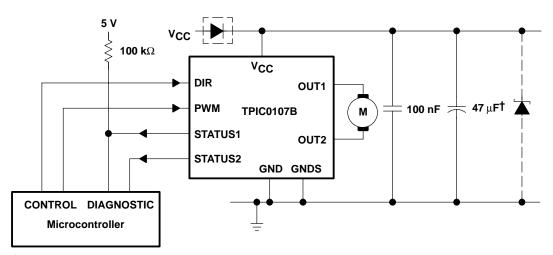


# STATIC-DRAIN-SOURCE ON-RESISTANCE **SUPPLY VOLTAGE** 600 $^{\Gamma}\text{DS(on)}^{-}$ Static Drain-Source On-Resistance – m $\Omega$ $HSD, T_J = 125^{\circ}C$ 500 LSD, $T_J = 125^{\circ}C$ 400 300 HSD, T<sub>J</sub> = 25°C LSD, $T_J = 25^{\circ}C$ 200 100 5 10 15 20 25 V<sub>CC</sub> - Supply Voltage - V Figure 7

#### **OUTPUT STAGE TURN-ON TIME**



#### **APPLICATION INFORMATION**



 $<sup>^{\</sup>dagger}$  Necessary for isolating supply voltage or interruption (e.g., 47  $\mu\text{F}).$ 

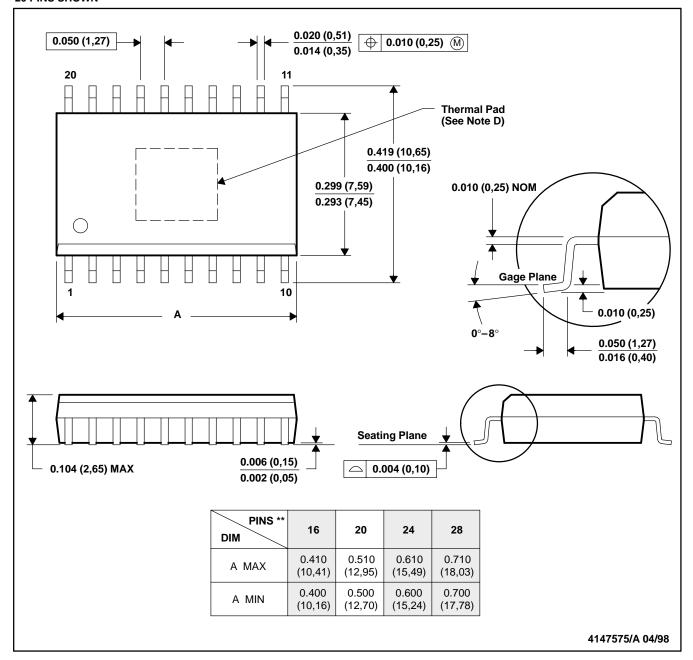
NOTE: If a STATUS output is not connected to the appropriate microcontroller input, it shall remain unconnected.

#### **MECHANICAL DATA**

#### DWP (R-PDSO-G\*\*)

#### PowerPAD™ PLASTIC SMALL-OUTLINE PACKAGE

20 PINS SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
  - D. The package thermal performance may be enhanced by bonding the thermal pad to an external thermal plane. This pad is electrically and thermally connected to the backside of the die and possibly selected leads.

PowerPAD is a trademark of Texas Instruments Incorporated.



#### **IMPORTANT NOTICE**

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third—party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Mailing Address:

Texas Instruments Post Office Box 655303 Dallas, Texas 75265

Copyright © 2002, Texas Instruments Incorporated